

JOURNAL OF SCIENCE



SAKARYA UNIVERSITY

Sakarya University Journal of Science

ISSN 1301-4048 | e-ISSN 2147-835X | Period Bimonthly | Founded: 1997 | Publisher Sakarya University |
<http://www.saujs.sakarya.edu.tr/>

Title: A Detailed Study on the Structural, Electrical and Optical Properties of (ZnO-GeO₂) Substituted In₂O₃ Transparent Conducting Oxide

Authors: Nazmi Sedefoglu

Received: 2018-12-04 00:00:00

Accepted: 2019-02-11 00:00:00

Article Type: Research Article

Volume: 23

Issue: 4

Month: August

Year: 2019

Pages: 610-616

How to cite

Nazmi Sedefoglu; (2019), A Detailed Study on the Structural, Electrical and Optical Properties of (ZnO-GeO₂) Substituted In₂O₃ Transparent Conducting Oxide.

Sakarya University Journal of Science, 23(4), 610-616, DOI:

10.16984/saufenbilder.492230

Access link

<http://www.saujs.sakarya.edu.tr/issue/43328/492230>

New submission to SAUJS

<http://dergipark.gov.tr/journal/1115/submission/start>

A Detailed Study on the Structural, Electrical and Optical Properties of (ZnO-GeO₂) Substituted In₂O₃ Transparent Conducting Oxide

Nazmi SEDEFOGLU*¹

Abstract

In this study, ZnO and GeO₂ substituted In₂O₃ ternary system is investigated with various characterization methods for optical, electrical and structural properties. This new transparent conducting oxide prepared different composition which can be symbolized as Zn_xIn_{2-2x}Ge_xO₃ 0.1 ≤ x ≤ 0.5. The optical properties of the samples obtained show that the optical band gap enhances from 2.94 eV to 3.16 eV with the augmentation of the x value. Conductivity values for x = 0.1 is about 308 S/cm and 1060 S/cm for unreduced and reduced samples respectively. The reduced conductivity of Zn_{0.476}In_{1.032}Ge_{0.476}O₃ is about 135 S/cm and for this composition samples are phase pure for new fluorite related phase. Thus, this study stresses the importance of cosubstitution to decrease amount of indium and understanding the various results for bulk samples.

Keywords: Zn and Ge substitution, Transparent Conducting Oxide, ZnO-In₂O₃-GeO₂ system, XRD

1. INTRODUCTION

In the past decade, significant development and innovation has been made on Transparent Conducting Oxide (TCO) due to its importance on building various devices like flat panel display and photovoltaic devices [1, 2]. The reason for this intense interest in TCOs is because of the fact that TCOs are degenerately doped semiconductor and highly transparent to visible radiation. So, these features allowed them to be used in future technologies. There are couple well known TCOs including In₂O₃:Sn (ITO), SnO₂:F and ZnO:Al [3, 4]. Among those of well known TCOs, ITO is the most widely used transparent conducting oxide material. However, Indium is a scarce metal and it is very expensive and low resource, researchers has been seeking for new TCOs to decrease the Indium content of its. Last two decades, many research groups have been searching for

cosubstitution [5]. For that purpose, two relatively cheaper materials have been chosen as constituent. As Freeman et al. [6] suggested, there are many novel compound and solid solution ceramic TCOs are not discovered. It has been decided that (2-3-4) ternary system which has Zn⁺² divalent, In⁺³ trivalent and Ge⁺⁴ tetravalent to obtain new bulk phase. For this reason, ZnO and GeO₂ has been chosen as constituent to the In₂O₃. In the ternaries phase space with (2-3-4) ternary system have shown B and S phase so far. There was not any T space for that system. In this study Zn⁺² and Ge⁺⁴ substituted into In₂O₃ and new phase space transformation for this special ternary system. This new phase has been identified as T-phase because of its tetragonal structure. There are some research groups who studied Ge doped In₂O₃ and Ge and Zn codoped In₂O₃. They have reported that Ge⁺⁴ doped In₂O₃ has very small solubility about 1%-1.5%, and there was observed secondary phases which affected sample densification and electric

* Corresponding Author

¹ Osmaniye Korkut Ata Üniversitesi Fen-Edebiyat Fakültesi, Fizik Bölümü, OSMANİYE-nazmisedefoglu@osmaniye.edu.tr

conductivity negatively [7]. For Ge⁺⁴ and Zn⁺² codoped system has been reported as very suitable for thermoelectric materials and has very high electric conductivity which has decreased with increasing doping concentration. Moreover, in this system, they observed GeO₂ is the secondary phase and there was not any evidence for the new ZIGO structure [8]. Before understanding of new phase, we should mention about ZnO-In₂O₃-GeO₂ system which has three oxides and each of these oxides crystallizes different way. To clarify, In₂O₃ has bixbyite crystalline structure which can be seen as distorted fluorite structure with missing anions from b site or d site and has space group (Ia₃) [9]. GeO₂ has isostructural rutile structure with space group (P4₂/mm) [10]. ZnO has tetrahedral wurtzite structure, where Zn⁺² and O⁻² coordinated by four Zn⁺² and O⁻² respectively and have a space group (P6₃mc) [11].

2. EXPERIMENTAL DETAILS

All ZIGO samples were synthesized by high temperature solid state reaction method. The starting materials to synthesize bulk ceramic were commercial oxide powders of GeO₂ (99.99% Sigma Aldrich), In₂O₃ (99.99% Alfa Aesar) and ZnO (99.99% Sigma Aldrich). The new bulk ceramic which can denote as $Zn_xIn_{2-2x}Ge_xO_3$

Table 1 The Composition of ZnO, In₂O₃ and GeO₂ ternary system

Name	ZnO	GeO ₂	In ₂ O ₃	Formulization
ZIGO10	10%	10%	90%	Zn _{0.1} In _{1.8} Ge _{0.1} O ₃
ZIGO20	20%	20%	80%	Zn _{0.2} In _{1.6} Ge _{0.2} O ₃
ZIGO30	30%	30%	70%	Zn _{0.3} In _{1.4} Ge _{0.3} O ₃
ZIGO40	40%	40%	60%	Zn _{0.4} In _{1.2} Ge _{0.4} O ₃
ZIGOB	48.39%	48.39%	51.61%	Zn _{0.476} In _{1.032} Ge _{0.476} O ₃
ZIGOC	47.62%	47.62%	52.38%	Zn _{0.484} In _{1.048} Ge _{0.484} O ₃
ZIGO50	50%	50%	50%	Zn _{0.5} In _{1.0} Ge _{0.5} O ₃

For being certain, PXRD measurement has been repeated with crystalline silica standard. In this way, device errors have been eliminated and calibration standard of peak positions in PXRD have been ensured. The Perkin Elmer 1050 UV-Vis-NIR spectrometer with Lambda 150 nm integrated sphere accessory allowed diffuse reflectance measurement are used for optical

for $0.1 \leq x \leq 0.5$ and stoichiometry of the samples are given in the Table 1. GeO₂, In₂O₃ and ZnO powder were weighted carefully with sensitivity about 1 milligram. All powders are mixed into agate mortar stoichiometrically and grinded about 10 minutes. After that, they were ground under acetone and put into drying oven. Then, dried mixture grinded again and pressed into a pellet with 13 mm diameter. Sacrificial powders were placed into the small alumina crucible then pressed pellet buried in same composition of sacrificial powder. Small crucible capped a lid and put into the bigger crucible. This method was thought as necessary to prevent Zn volatilization and keep reaction isovalent [12, 13]. Samples were sintered at a furnace programmed as heating 20 °C per minute to temperature 1250 °C dwelled at this temperature for 16h and cooled down to room temperature 10°C per minute. X-ray powder diffraction analysis of ZIGO was performed at room temperature in the angular range of $2\theta = 20^\circ - 70^\circ$ with scan step of 0.1° and a continuous counting time of 4° per minute using an automated Rigaku X-Ray diffractometer equipped with Cu α radiation of wavelength $\lambda = 1.5418 \text{ \AA}$.

characterization of samples which has been measure wavelength between 300-800 nm. Electrical conductivity measurement of pellets were taken at room temperature in four point probe geometry configuration [14, 15].

3. RESULTS and DISCUSSIONS

In Figure 1 and 2, XRD pattern of sintered ZIGO samples have been showed. The XRD showed clearly the evolution of new phase. ZIGO10 showed highly dominated bixbyite phase. Bixbyite 222 peak and adequately big new phase most dominant peak can be seen at 30.763° (bixbyite 222) and 31.283° respectively. While further decreased In₂O₃ concentration in the samples, bixbyite phase was disappeared, and new phase diffraction peaks became dominant. Increasing concentration of ZnO and GeO₂ shows Ge and Zn became structural elements rather than substitutional one. Zn_{0.476}In_{1.032}Ge_{0.476}O₃ is the exact formulation of new ZnO-In₂O₃-GeO₂ system [16]. According to formulization, about 47% molar percent of Indium has removed from samples. For this sensivity of PXRD results Zn_{0.476}In_{1.032}Ge_{0.476}O₃ formulation does not show any secondary phases. It has not been indexed with any discovered ZnO-In₂O₃-GeO₂ bulk

system or reaction with alumina crucible. However, Rickert et al. [17] indexed that Zn_{0.456}In_{1.084}Ge_{0.460}O₃ (ZIGO) contained three phases and this new phase not related to bixbyite on the contrary it is fluorite related tetragonal phases. The product of high temperature samples exhibited XRD pattern with peak characteristic tetragonal phase structure. Major peaks of this phase are similar to bixbyite which is to be expected as lanthanides and actinides form various fluoride related phases. PXRD results with Silica standard are used to determine exact position of diffraction patterns. So diffractograms with and without Silica standard illustrate several interesting features regarding to new system consequently [18]. Firstly, any thought of the new diffraction peaks is the shifts of bixbyite phase are refuted because of Silica standard PXRD peaks. Secondly, it can comfortably say that while looking these four most intense peaks of bixbyite structure disappear via increasing Zn⁺²/Ge⁺⁴ composition. In other word, bixbyite phase disapper by adding Zn⁺²/Ge⁺⁴ substitutions.

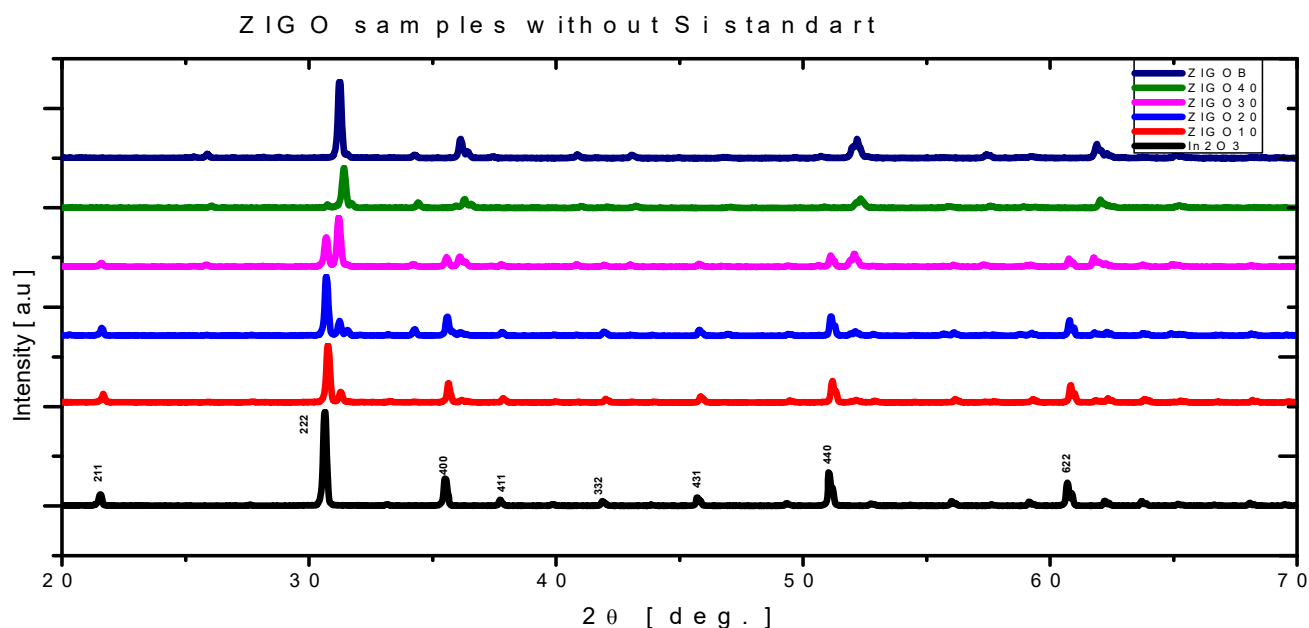


Figure 1 PXRD results of Zn-In-Ge-O ternary system without Silica standard. Black plots represent bixbyite hkl indexes (colored)

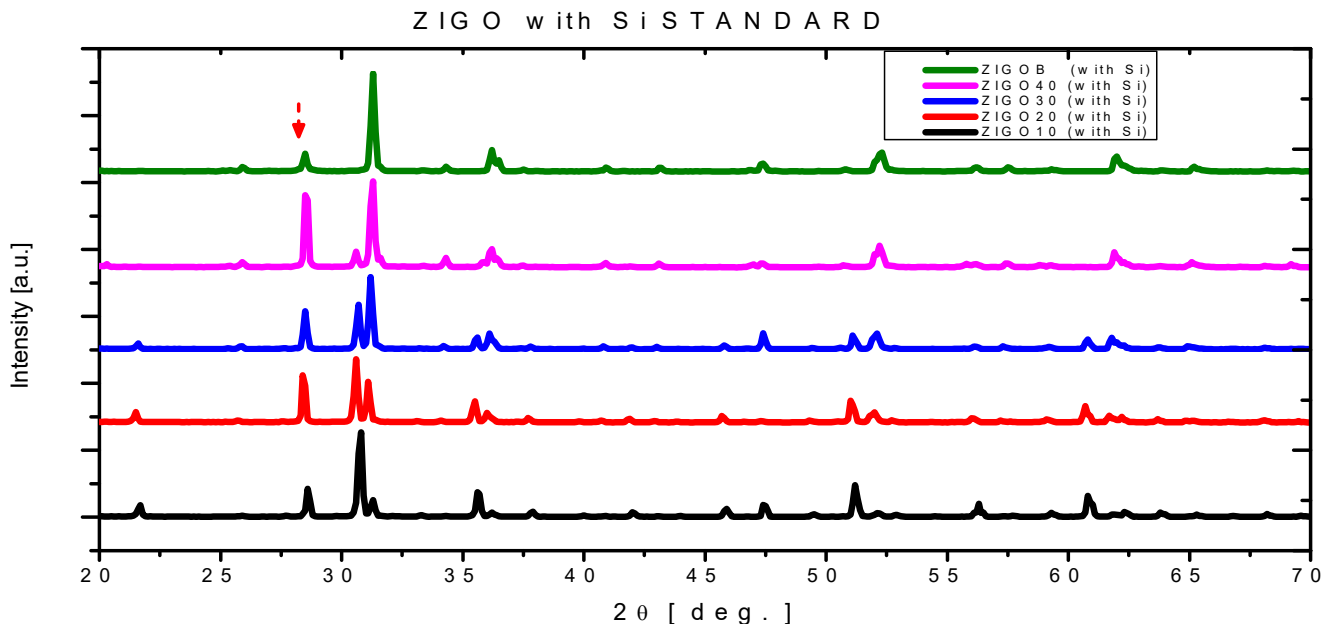


Figure 2 PXRD results of Zn-In-Ge-O ternary system with Silica standard (Red arrow indicates (111) Si internal standard peaks in samples) (colored)

All the prepared samples in this study have been plotted by composition in the Figure 3. In Figure 3, edges are ZnO-In₂O₃-GeO₂ and it is seen in the Figure 3 that ZnO-GeO₂ ratio was kept equal for all [5]. Further experiment can be conducted to

fill empty space in Figure 3. In the binary system ZnO-In₂O₃ and In₂O₃-GeO₂, just one binary compound cubic bixbyite was reported in previous studies [7, 8, 19].

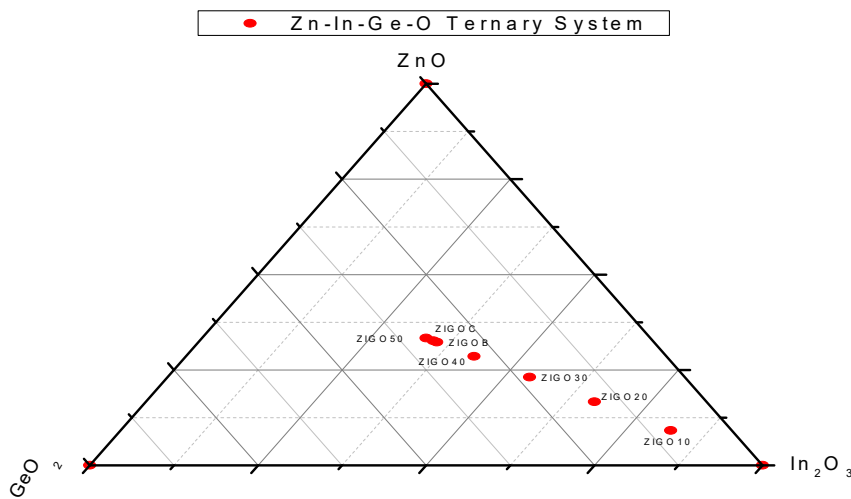


Figure 3 Subsolidus phase relations in Zn-In-Ge-O system (colored)

Electrical conductivity of reported ternary system as a function of In³⁺ content is given in Figure 4 and porosity corrections are made by the Bruggemann symmetric model [14]. The electrical conductivity of pellet samples for Zn_{0.1}In_{1.8}Ge_{0.1}O₃ composition is 308 S/cm and

1060 S/cm for unreduced and reduced samples respectively. The reduced conductivity of Zn_{0.476}In_{1.032}Ge_{0.476}O₃ decreased up to 135 S/cm [17, 20-22]. Conductivity results indicate that this new system has similar conductivity behavior of other In₂O₃ based ternary system [21, 22].

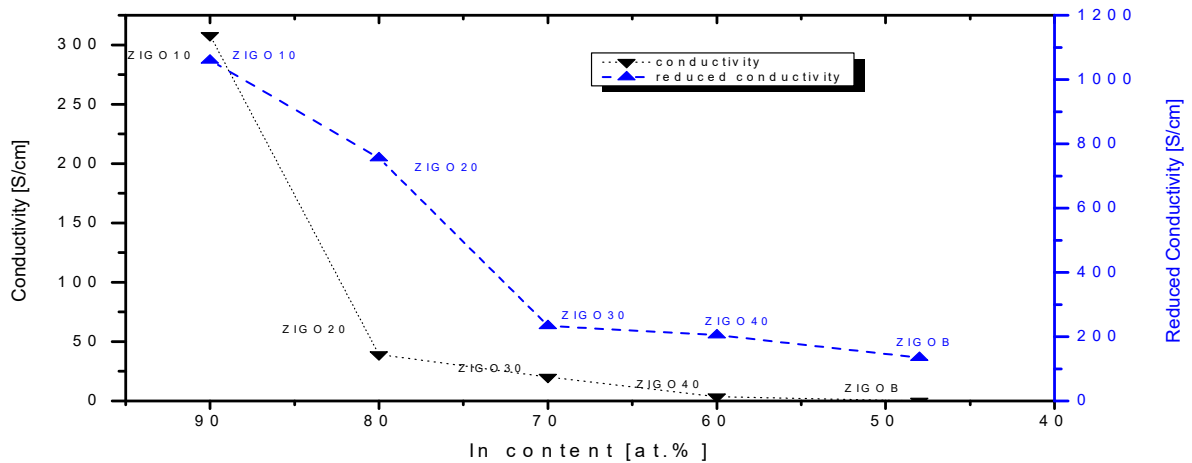


Figure 4 Reduced and unreduced electrical conductivity of ZIGO samples (colored)

Reduced and unreduced samples conductivity is increasing with the decrement of ZnO and GeO₂ substitution regard to In₂O₃. This result shows that new phase ZIGO system has not superior electric properties with respect to ITO [23]. For conductivity point of view, it should be note that composition and conductivity properties look similar with ITO. As mentioned above, samples stoichiometry can be denoted as Zn_xIn_{2-2x}Ge_xO₃ (0.1 ≤ x ≤ 0.5) and for increasing ZnO and GeO₂ substitution regard to In₂O₃ has increased optical band gap of new materials owing to substitutions wide band gap [24]. Samples optical band gap estimated with Kubalka Munk function [25] is given below

$$F(R_{\infty}) = \frac{K}{S} = \frac{(1-R_{\infty})^2}{2R_{\infty}} \quad (1)$$

where K-M are the absorption and scattering coefficient respectively and R_∞ is reflectance of specimen. The absorption coefficient in the equation 1 can be related to the optical band gap with Tauc equation [26] as written below

$$ahv = C_1(hv - E_g)^y \quad (2)$$

$$(ahv)^{\frac{1}{y}} = C_2(hv - E_g) \quad (3)$$

Samples conductivities are 2.94 eV, 2.99 eV, 3.05eV, 3.14 eV and 3.16 eV for x= 0.1, 0.2, 0.3, 0.4 and 0.456 respectively. The fundamental absorption edge for given composition is around 400 nm similar to In₂O₃ [27]. By adding substitutant into sample, optical bandgap shifted

the larger energies and reflectance shifted to lower wavelength [28].

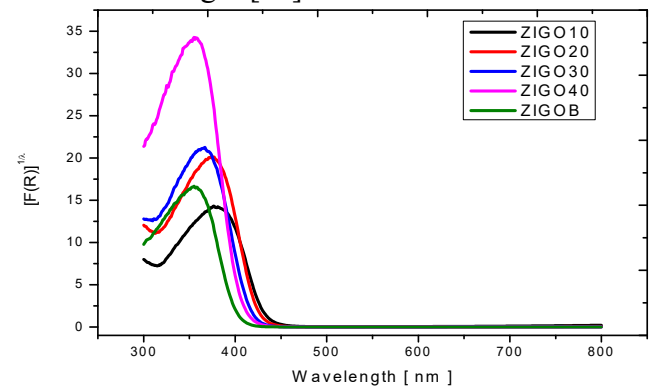


Figure 5 F(R) versus wavelength spectra of various compositions (colored)

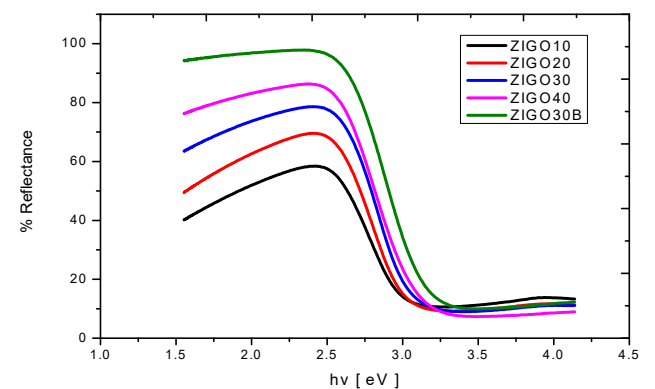


Figure 6 Diffuse Reflectance versus hv spectra of various compositions (colored)

4. CONCLUSION

It has been presented that ZnO and GeO₂ cosubstituted regard to In₂O₃ are very promising replacement to for ITO. Here phase relation of ZnO-In₂O₃-GeO₂ system has been established successfully. ZIGO has less amount of In₂O₃ than ITO which decreases the cost of this system dramatically. New TCO contains 47% less indium. However electronic properties of ZIGO have not succeeded ITO's electronic properties. Thin films studies must be conducted on this system. Pure phase ZIGO has band gap 3.16 eV. The phase diagram of this system is shown in Figure 3. Excess amount of Zn⁺² and Ge⁺⁴ studies could be a suitable alternative for carrier mechanism and can break new ground on conductivity properties of this new system.

REFERENCES

- [1] K. L. Chopra, S. Major, and D. K. Pandya, "Transparent conductors-A status review," *Thin Solid Films*, vol. 102, pp. 1-46, 1983.
- [2] H. Ohta and H. Hosono, *Mater. Today*, vol. JUNE, p. 42, 2004.
- [3] H. Kawazoe, H. Yanagi, K. Ueda, and H. Hosono, "Transparent p-Type Conducting Oxides: Design and Fabrication of p-n Heterojunctions," *MRS Bulletin*, vol. 25, pp. 28-36, 2011.
- [4] G. Frank and H. Köstlin, "Electrical properties and defect model of tin-doped indium oxide layers," *Applied Physics A*, vol. 27, pp. 197-206, April 01 1982.
- [5] A. Ambrosini, A. Duarte, K. R. Poeppelmeier, M. Lane, C. R. Kannewurf, and T. O. Mason, "Electrical, Optical, and Structural Properties of Tin-Doped In₂O₃-M₂O₃ Solid Solutions (M=Y, Sc)," *Journal of Solid State Chemistry*, vol. 153, pp. 41-47, 2000/08/01/ 2000.
- [6] A. J. Freeman, K. R. Poeppelmeier, T. O. Mason, R. P. H. Chang, and T. J. Marks, "Chemical and thin-film strategies for new transparent conducting oxides," *MRS Bulletin*, vol. 25, pp. 45-51, 2000.
- [7] D. Bérardan, E. Guilmeau, A. Maignan, and B. Raveau, "In₂O₃:Ge, a promising n-type thermoelectric oxide composite," *Solid State Communications*, vol. 146, pp. 97-101, 2008.
- [8] B. Cheng, H. Fang, J. Lan, Y. Liu, Y. H. Lin, and C. W. Nan, "Thermoelectric performance of Zn and Ge Co-Doped In₂O₃ fine-grained ceramics by the spark plasma sintering," *Journal of the American Ceramic Society*, vol. 94, pp. 2279-2281, 2011.
- [9] M. Marezio, "Refinement of the crystal structure of In₂O₃ at two wavelengths," *Acta Crystallogr.*, vol. 20, pp. 723-728, 1966.
- [10] V. M. Goldschmidt, T. Barth, and G. Lunde, "Isomorphie und Polymorphie der Sesquioxide. Die Lanthaniden-Kontraktion und ihre Konsequenzen," *Skr. Nor. Vidensk.-Akad.: Mat. - Naturvidensk. Kl.*, vol. 7, pp. 1-59, 1925.
- [11] S. C. Abrahams and J. L. Bernstein, "Remeasurement of the structure of hexagonal ZnO," *Acta Crystallographica Section B*, vol. 25, pp. 1233-1236, 1969.
- [12] G. B. Palmer, K. R. Poeppelmeier, and T. O. Mason, "Conductivity and transparency of ZnO/SnO₂-cosubstituted In₂O₃," *Chemistry of Materials*, vol. 9, pp. 3121-3126, Dec 1997.
- [13] S. P. Harvey, K. R. Poeppelmeier, and T. O. Mason, "Subsolidus phase relationships in the ZnO-In₂O₃-SnO₂ system," *Journal of the American Ceramic Society*, vol. 91, pp. 3683-3689, 2008.
- [14] D. S. McLachlan, M. Blaszkiewicz, and R. E. Newnham, "Electrical Resistivity of Composites," *Journal of the American Ceramic Society*, vol. 73, pp. 2187-2203, 1990.
- [15] F. M. Smits, "Measurement of sheet resistivities with the four-point probe," *The Bell System Technical Journal*, vol. 37, pp. 711-718, 1958.
- [16] D. D. Edwards, T. O. Mason, F. Goutenoire, and K. R. Poeppelmeier, "A new transparent conducting oxide in the Ga₂O₃-In₂O₃-SnO₂ system," *Applied*

- Physics Letters*, vol. 70, pp. 1706-1708, 1997.
- [17] K. Rickert, N. Sedefoglu, S. Malo, V. Caignaert, H. Kavak, and K. R. Poepelmeier, "Structural, Electrical, and Optical Properties of the Tetragonal, Fluorite-Related Zn_{0.456}In_{1.084}Ge_{0.460}O₃," *Chemistry of Materials*, vol. 27, pp. 5072-5079, 2015.
- [18] J. G. M. van Berkum, G. J. M. Sprong, T. H. de Keijser, R. Delhez, and E. J. Sonneveld, "The optimum standard specimen for X-ray diffraction line-profile analysis," *Powder Diffraction*, vol. 10, pp. 129-139, 2013.
- [19] M. N. Fujii, Y. Ishikawa, R. Ishihara, J. v. d. Cingel, M. R. T. Mofrad, J. P. S. Bermundo, *et al.*, "Nano-crystallization in ZnO-doped In₂O₃ thin films via excimer laser annealing for thin-film transistors," *AIP Advances*, vol. 6, p. 065216, 2016.
- [20] K. Rickert, J. Harris, N. Sedefoglu, H. Kavak, D. E. Ellis, and K. R. Poepelmeier, "Site identity and importance in cosubstituted bixbyite In₂O₃," *Crystals*, vol. 7, 2017.
- [21] L. Bizo, J. Choisnet, and B. Raveau, "Coupled substitutions in In₂O₃: New transparent conductors In_{2-x}M_{2x/3}Sb_{x/3}O₃ (M = Cu, Zn)," *Materials Research Bulletin*, vol. 41, pp. 2232-2237, Dec 14 2006.
- [22] D. Berardan, E. Guilmeau, A. Maignan, and B. Raveau, "Enhancement of the thermoelectric performances of In₂O₃ by the coupled substitution of M⁽²⁺⁾/Sn⁽⁴⁺⁾ for In⁽³⁺⁾," *Journal of Applied Physics*, vol. 104, Sep 15 2008.
- [23] D. Berardan, E. Guilmeau, A. Maignan, and B. Raveau, "In₂O₃ : Ge, a promising n-type thermoelectric oxide composite," *Solid State Communications*, vol. 146, pp. 97-101, Apr 2008.
- [24] A. Dolgonos, K. Lam, K. R. Poepelmeier, A. J. Freeman, and T. O. Mason, "Electronic and optical properties of Ga_{3-x}In_{5+x}Sn₂O₁₆: An experimental and theoretical study," *Journal of Applied Physics*, vol. 115, p. 013703, 2014.
- [25] P. Kubelka and F. Munk, "Ein Beitrag zur Optik der Farbanstriche," *Z. Tech. Phys.*, vol. 12, pp. 593-601, 1931.
- [26] J. Tauc, "Optical properties and electronic structure of amorphous Ge and Si," *Materials Research Bulletin*, vol. 3, pp. 37-46, 1968.
- [27] R. L. Weiher and R. P. Ley, "Optical Properties of Indium Oxide," *Journal of Applied Physics*, vol. 37, pp. 299-302, 1966.
- [28] J. Choisnet, L. Bizo, R. Retoux, and B. Raveau, "Antimony and antimony-tin doped indium oxide, IAO and IATO: Promising transparent conductors," *Solid State Sciences*, vol. 6, pp. 1121-1123, 2004.